Search Notes

Application/Control No.		Applicant(s)/Patent under Reexamination	
10/766,208	FURUKAWA ET AL.		
Examiner	Art Unit		
Le Nguyen	2174		

SEARCHED					
Class	Subclass	Date	Examiner		
715	745	3/28/2007	LVN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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	b, USPAT: /745	3/28/2007	LVN	

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
inventor name search	3/28/2007	LVN
US-PGPub, USPAT: 715/745,748,742; 705/400-411,64; 709/206	3/28/2007	LVN
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